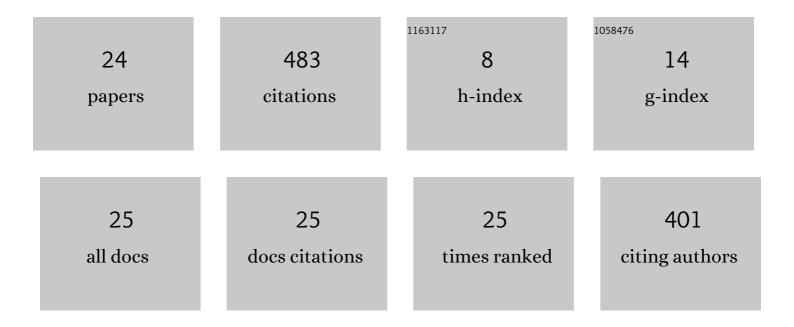
Fernando M D Goncalves

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/2662332/publications.pdf Version: 2024-02-01



#	Article	IF	CITATIONS
1	Design and evaluation of the clear-PEM scanner for positron emission mammography. IEEE Transactions on Nuclear Science, 2006, 53, 71-77.	2.0	111
2	TOFPET ASIC for PET applications. Journal of Instrumentation, 2013, 8, C02050-C02050.	1.2	98
3	Defect level evaluation in an IC design environment. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 1996, 15, 1286-1293.	2.7	37
4	A methodology for testability enhancement at layout level. Journal of Electronic Testing: Theory and Applications (JETTA), 1991, 1, 287-299.	1.2	28
5	Clear-PEM: A PET imaging system dedicated to breast cancer diagnostics. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2007, 571, 81-84.	1.6	26
6	Experimental characterization of the 192 channel Clear-PEM frontend ASIC coupled to a multi-pixel APD readout of LYSO:Ce crystals. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2009, 598, 802-814.	1.6	25
7	The Clear-PEM Electronics System. IEEE Transactions on Nuclear Science, 2006, 53, 2704-2711.	2.0	20
8	Performanceâ€driven instrumentation and mapping strategies using the LARA aspectâ€oriented programming approach. Software - Practice and Experience, 2016, 46, 251-287.	3.6	20
9	A 64-channel ASIC for TOFPET applications. , 2012, , .		19
10	Physical design of testable CMOS digital integrated circuits. IEEE Journal of Solid-State Circuits, 1991, 26, 1064-1072.	5.4	17
11	REFLECT: Rendering FPGAs to Multi-core Embedded Computing. , 2011, , 261-289.		14
12	High-Level Synthesis in the Delft Workbench Hardware/Software Co-design Tool-Chain. , 2014, , .		10
13	RTL-Based Functional Test Generation for High Defects Coverage in Digital Systems. Journal of Electronic Testing: Theory and Applications (JETTA), 2001, 17, 311-319.	1.2	9
14	Performance Simulation Studies of the Clear-PEM DAQ/Trigger System. IEEE Transactions on Nuclear Science, 2006, 53, 2102-2111.	2.0	8
15	Defect-oriented testing of analogue and mixed signal ICs. , 0, , .		6
16	Defect-Oriented Sampling of Non-Equally Probable Faults in VLSI Systems. Journal of Electronic Testing: Theory and Applications (JETTA), 1999, 15, 41-52.	1.2	6
17	An overview of the Clear-PEM breast imaging scanner. , 2008, , .		6

18 Characterization of the Clear-PEM breast imaging scanner performance. , 2009, , .

6

#	Article	IF	CITATIONS
19	Performance simulation studies of the clear-PEM DAQ/trigger system. , 2005, , .		5
20	Low Energy Heterogeneous Computing with Multiple RISC-V and CGRA Cores. , 2019, , .		4
21	Design and Test of a Certifiable ASIC for a Safety-Critical Gas Burner Control System. Journal of Electronic Testing: Theory and Applications (JETTA), 2002, 18, 285-294.	1.2	3
22	High-speed Data Acquisition Electronics for a PEM scanner. , 2009, , .		3
23	RTL Design Validation, DFT and Test Pattern Generation for High Defects Coverage. Journal of Electronic Testing: Theory and Applications (JETTA), 2002, 18, 179-187.	1.2	1
24	Hardware/software specialization through aspects: The LARA approach. , 2012, , .		1